

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit	Page 1 of 1
Joseph D. Torres		2133	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,709,366 A	11-1987	Scott et al.	714/46
*	C	US-5,341,314 A	08-1994	Bencivenga et al.	716/4
*	D	US-5,377,201 A	12-1994	Chakradhar et al.	714/741
*	E	US-6,618,826 B1	09-2003	Chen et al.	714/718
*	F	US-5,958,077 A	09-1999	Banerjee et al.	714/738
*	G	US-6,044,214 A	03-2000	Kimura et al.	703/15
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Song, O.; Menon, P.R.; Parallel pattern fault simulation based on stem faults in combinational circuits, Proceedings International Test Conference, 10-14 Sept. 1990, Pages:706 - 711
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.